

# AUIRFIZ34NPBF-VB Datasheet N-Channel 60 V (D-S) MOSFET

PRODUCT SUMMARY				
V <sub>DS</sub> (V)	60			
$R_{DS(on)}\left(\Omega\right)$	V <sub>GS</sub> = 10 V	0.027		
Q <sub>g</sub> (Max.) (nC)	95			
Q <sub>gs</sub> (nC)	27			
Q <sub>gd</sub> (nC)	46			
Configuration	Single			

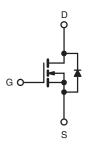
#### **FEATURES**

- · Isolated Package
- High Voltage Isolation = 2.5 kV<sub>RMS</sub> (t = 60 s;



- Sink to Lead Creepage Distance = 4.8 mm
- 175 °C Operating Temperature
- · Dynamic dV/dt Rating
- · Low Thermal Resistance
- Lead (Pb)-free Available





N-Channel MOSFET

 $T_J$ ,  $T_{stg}$ 

- 55 to + 175

300d 10

1.1

ABSOLUTE MAXIMUM RATINGS T <sub>C</sub> = 25 °C, unless otherwise noted						
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			$V_{DS}$	60	- V	
Gate-Source Voltage			$V_{GS}$	± 20		
Continuous Drain Current	V <sub>GS</sub> at 10 V	$T_{\rm C} = 25  ^{\circ}{\rm C}$ $T_{\rm C} = 100  ^{\circ}{\rm C}$	I <sub>D</sub>	45	А	
	VGS at 10 V	$T_C = 100 ^{\circ}C$		30		
Pulsed Drain Current <sup>a</sup>			$I_{DM}$	220		
Linear Derating Factor			0.32	W/°C		
Single Pulse Avalanche Energy <sup>b</sup>		E <sub>AS</sub>	100	mJ		
Maximum Power Dissipation	T <sub>C</sub> =	T <sub>C</sub> = 25 °C		52	W	
Peak Diode Recovery dV/dt <sup>c</sup>		dV/dt	4.5	V/ns		

for 10 s

6-32 or M3 screw

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b.  $V_{DD}=25$  V, starting  $T_J=25$  °C, L=129  $\mu H,~R_G=25$   $\Omega,~I_{AS}=30$  A (see fig. 12). c.  $I_{SD}\leq 52$  A,  $dI/dt\leq 250$  A/ $\mu s,~V_{DD}\leq V_{DS},~T_J\leq 175$  °C.

Operating Junction and Storage Temperature Range

Soldering Recommendations (Peak Temperature)

d. 1.6 mm from case.

Mounting Torque

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°С

lbf ⋅ in

 $N\cdot m \\$ 



THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient	R <sub>thJA</sub>	-	65	°C/W	
Maximum Junction-to-Case (Drain)	R <sub>thJC</sub>	=	3.1	C/VV	

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static							•
Drain-Source Breakdown Voltage	V <sub>DS</sub>	V <sub>GS</sub> :	60	-	-	V	
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	-	0.060	-	V/°C	
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$		1.0	-	3.0	V
Gate-Source Leakage	I <sub>GSS</sub>	V <sub>GS</sub> = ± 20 V		-	-	± 100	nA
Zana Oata Wallana Busin Oamani		V <sub>DS</sub> = 60 V, V <sub>GS</sub> = 0 V		-	-	25	μΑ
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = 48 V	V <sub>DS</sub> = 48 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 150 °C		-	250	
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 18 A <sup>b</sup>	-	0.027	-	Ω
Forward Transconductance	9 <sub>fs</sub>	V <sub>DS</sub> :	V <sub>DS</sub> = 25 V, I <sub>D</sub> = 18 A <sup>b</sup>		-	-	S
Dynamic							•
Input Capacitance	C <sub>iss</sub>	$V_{GS} = 0 \text{ V},$ $V_{DS} = 25 \text{ V},$ $f = 1.0 \text{ MHz}, \text{ see fig. 5}$		-	1500	-	pF
Output Capacitance	C <sub>oss</sub>			-	720	-	
Reverse Transfer Capacitance	C <sub>rss</sub>			-	100	-	
Drain to Sink Capacitance	С			-	12	-	
Total Gate Charge	Qg		I <sub>D</sub> = 52 A, V <sub>DS</sub> = 48 V, see fig. 6 and 13 <sup>b</sup>	-	-	95	nC
Gate-Source Charge	Q <sub>gs</sub>	V <sub>GS</sub> = 10 V		-	-	27	
Gate-Drain Charge	Q <sub>gd</sub>	1		-	-	46	
Turn-On Delay Time	t <sub>d(on)</sub>	$V_{DD} = 30 \text{ V}, I_{D} = 52 \text{ A},$ $R_{G} = 9.1 \Omega, R_{D} = 0.54 \Omega,$ see fig. $10^{b}$		-	19	-	- ns
Rise Time	t <sub>r</sub>			-	120	-	
Turn-Off Delay Time	t <sub>d(off)</sub>			-	55	-	
Fall Time	t <sub>f</sub>			-	86	-	
Internal Drain Inductance	L <sub>D</sub>	Between lead, 6 mm (0.25") from package and center of die contact		-	4.5	-	-11
Internal Source Inductance	L <sub>S</sub>			-	7.5	-	- nH
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I <sub>S</sub>	MOSFET symbol showing the integral reverse p - n junction diode		-	-	45	- A
Pulsed Diode Forward Current <sup>a</sup>	I <sub>SM</sub>			-	-	120	
Body Diode Voltage	$V_{SD}$	$T_J = 25  ^{\circ}\text{C},  I_S = 30  \text{A},  V_{GS} = 0  \text{V}^{\text{b}}$		-	-	2.5	V
Body Diode Reverse Recovery Time	t <sub>rr</sub>	- T <sub>J</sub> = 25 °C, I <sub>F</sub> = 52 A, dl/dt = 100 A/μs <sup>b</sup>		-	140	300	ns
Body Diode Reverse Recovery Charge	$Q_{rr}$			-	1.2	2.8	μC
Forward Turn-On Time	t <sub>on</sub>	Intrinsic turn-on time is negligible (turn-on is dominate				$L_{\rm S}$ and $L$	_D)

#### Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Pulse width  $\leq$  300  $\mu$ s; duty cycle  $\leq$  2 %.

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#### TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

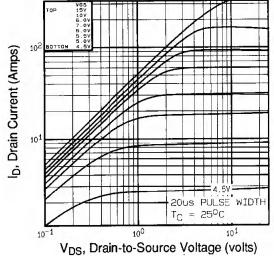


Fig. 1 - Typical Output Characteristics, T<sub>C</sub> = 25 °C

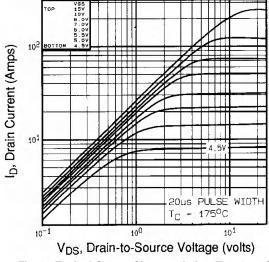


Fig. 2 - Typical Output Characteristics, T<sub>C</sub> = 175 °C

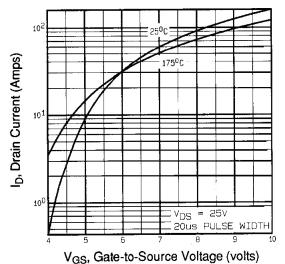


Fig. 3 - Typical Transfer Characteristics

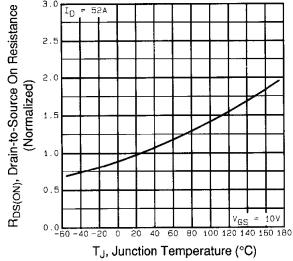


Fig. 4 - Normalized On-Resistance vs. Temperature



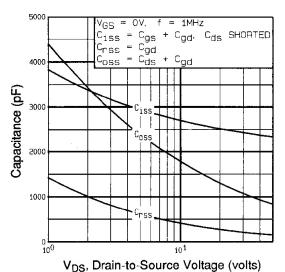


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

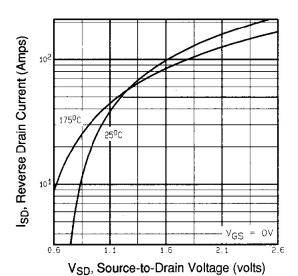


Fig. 7 - Typical Source-Drain Diode Forward Voltage

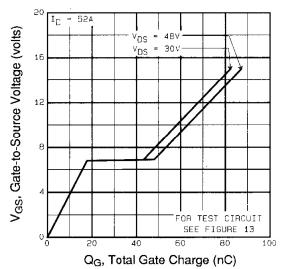
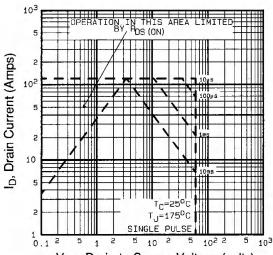


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage



V<sub>DS</sub>, Drain-to-Source Voltage (volts) Fig. 8 - Maximum Safe Operating Area

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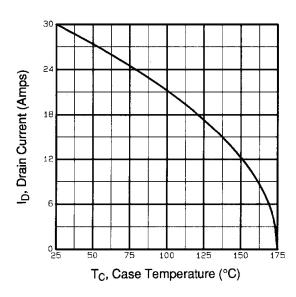


Fig. 9 - Maximum Drain Current vs. Case Temperature

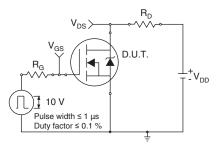


Fig. 10a - Switching Time Test Circuit

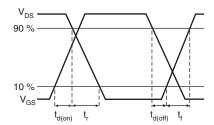


Fig. 10b - Switching Time Waveforms

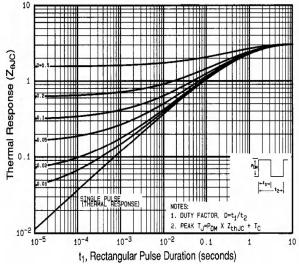


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

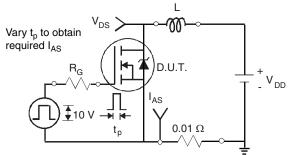


Fig. 12a - Unclamped Inductive Test Circuit

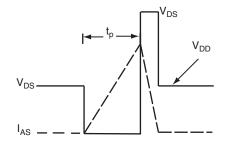
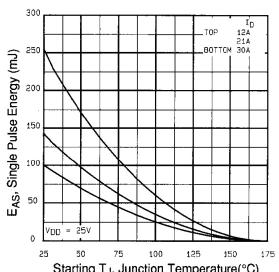


Fig. 12b - Unclamped Inductive Waveforms





 $Starting \ T_J, \ Junction \ Temperature (^{\circ}C)$  Fig. 12c - Maximum Avalanche Energy vs. Drain Current

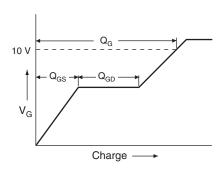


Fig. 13a - Basic Gate Charge Waveform

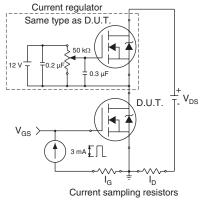
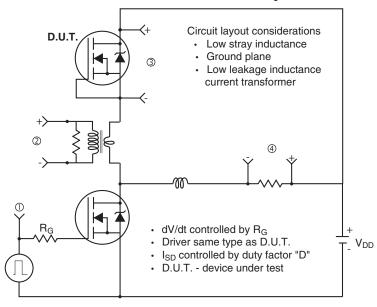


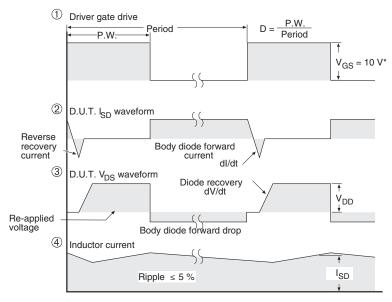
Fig. 13b - Gate Charge Test Circuit

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### Peak Diode Recovery dV/dt Test Circuit





\*  $V_{GS} = 5 V$  for logic level devices

Fig. 14 - For N-Channel

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